

### Features

- 60V/33A,  
 $R_{DS(ON)} = 13m\Omega(Typ.)@V_{GS}=10V$   
 $R_{DS(ON)} = 15m\Omega(Typ.)@V_{GS}=4.5V$
- Super High Dense Cell Design
- Fast Switching Speed
- 100% avalanche tested

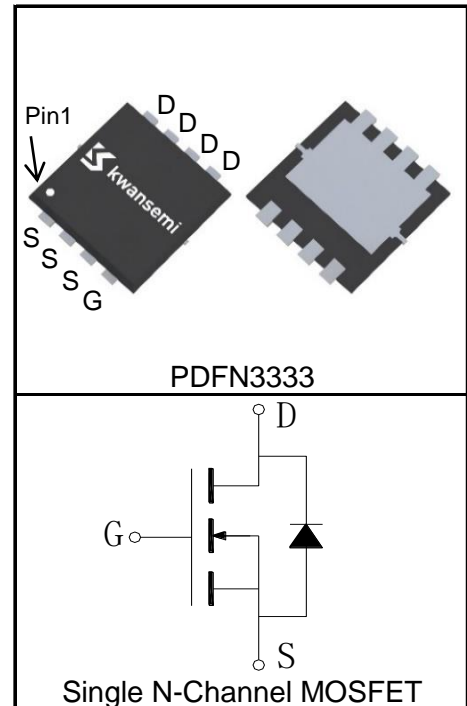
### Applications

- Switching Application Systems



Halogen-Free

### Pin Description



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit
<b>Common Ratings</b> ( $T_C=25^\circ C$ Unless Otherwise Noted)			
$V_{DSS}$	Drain-Source Voltage	60	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$T_{Jmax}$	Maximum Junction Temperature	150	$^\circ C$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ C$
$I_S$	Diode Continuous Forward Current	$T_C=25^\circ C$ 33	A
<b>Mounted on Large Heat Sink</b>			
$I_{DP}^{①}$	Pulse Drain Current	$T_C=25^\circ C$ 132	A
$I_D^{②}$	Continuous Drain Current@ $T_C(V_{GS}=10V)$	$T_C=25^\circ C$ 33	A
		$T_C=100^\circ C$ 20	
	Continuous Drain Current@ $T_A(V_{GS}=10V)^{③}$	$T_A=25^\circ C$ 10	
		$T_A=70^\circ C$ 8	
$P_D$	Maximum Power Dissipation@ $T_C$	$T_C=25^\circ C$ 32	W
		$T_C=100^\circ C$ 13	
	Maximum Power Dissipation@ $T_A^{③}$	$T_A=25^\circ C$ 3.5	
		$T_A=70^\circ C$ 2.3	

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	3.8	°C/W
$R_{\theta JA}$ ③	Thermal Resistance-Junction to Ambient	35	°C/W
<b>Drain-Source Avalanche Ratings</b>			
$E_{AS}$ ④	Avalanche Energy, Single Pulsed	110	mJ

**Electrical Characteristics** ( $T_C=25^\circ\text{C}$  Unless Otherwise Noted)

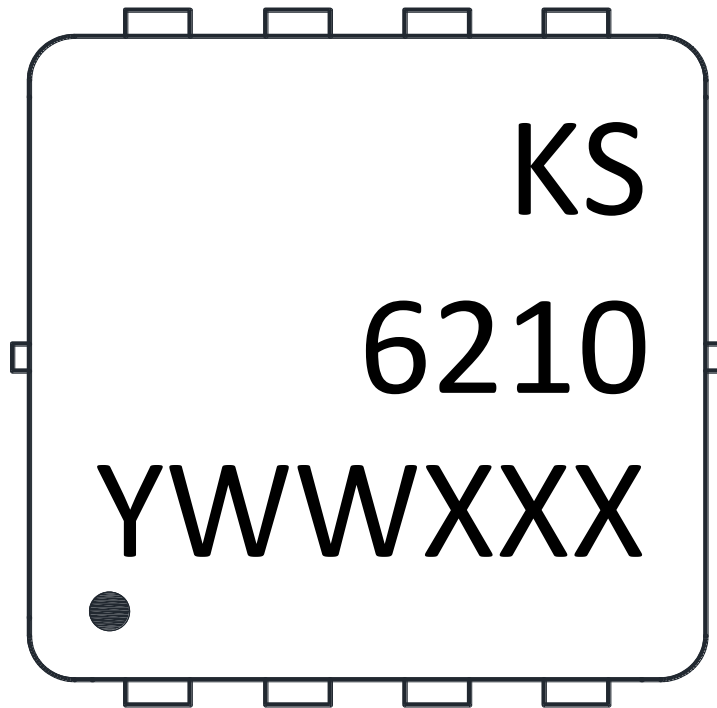
Symbol	Parameter	Test Condition	KS6210MB			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	60			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=60V, V_{GS}=0V$			1	$\mu A$
		$T_J=125^\circ\text{C}$			30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	1.2	1.7	2.3	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$			$\pm 100$	nA
$R_{DS(ON)}$ ⑤	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=20A$		13	16	$m\Omega$
		$V_{GS}=4.5V, I_{DS}=15A$		15	20	$m\Omega$
<b>Diode Characteristics</b>						
$V_{SD}$ ⑤	Diode Forward Voltage	$I_{SD}=20A, V_{GS}=0V$		0.87	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_{SD}=20A, dI_{SD}/dt=100A/\mu s$		25		ns
$Q_{rr}$	Reverse Recovery Charge			37		nC
<b>Dynamic Characteristics</b> ⑥						
$R_G$	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$		2.1		$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=30V, \text{Frequency}=1.0\text{MHz}$		2635		$\mu F$
$C_{oss}$	Output Capacitance			110		
$C_{riss}$	Reverse Transfer Capacitance			100		
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=30V, I_{DS}=20A, V_{GS}=10V, R_G=3\Omega$		14		ns
$t_r$	Turn-on Rise Time			22		
$t_{d(OFF)}$	Turn-off Delay Time			43		
$t_f$	Turn-off Fall Time			21		
<b>Gate Charge Characteristics</b> ⑥						
$Q_g$	Total Gate Charge	$V_{DS}=30V, V_{GS}=10V, I_{DS}=20A$		51		nC
$Q_{gs}$	Gate-Source Charge			7.5		
$Q_{gd}$	Gate-Drain Charge			11		

**Notes:**

- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature.
- ③When mounted on 1 inch square copper board,  $t \leq 10\text{sec}$ .
- ④Limited by  $T_{Jmax}$ , Starting  $T_J = 25^\circ\text{C}$ ,  $I_{ASmax} = 21\text{A}$ ,  $L=0.5\text{mH}$ ,  $V_{DD} = 30\text{V}$ ,  $R_G = 25\Omega$ ,  $V_{GS}=10\text{V}$ .Part not recommended for use above this value.100% Final Test at  $I_{AS}=10\text{A}$ ,  $L=0.5\text{mH}$ .
- ⑤Pulse test;Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .
- ⑥Guaranteed by design, not subject to production testing.

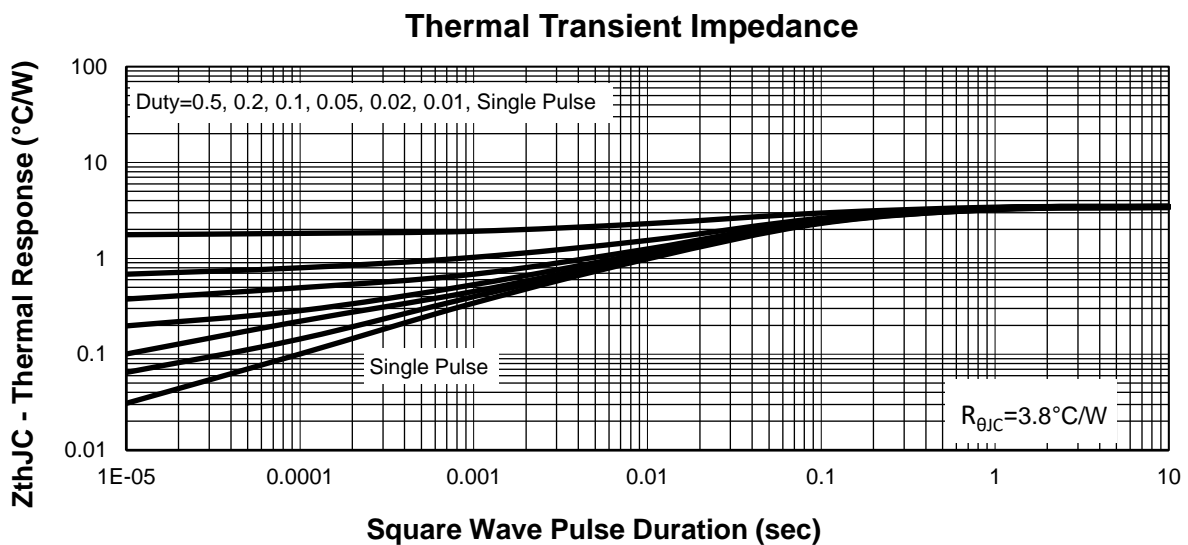
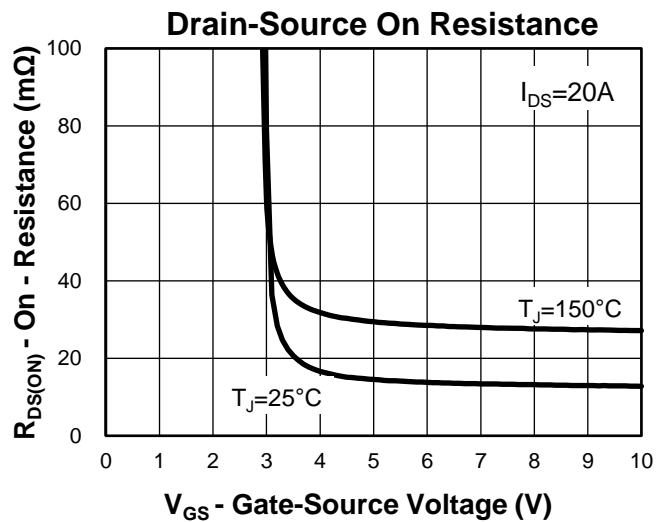
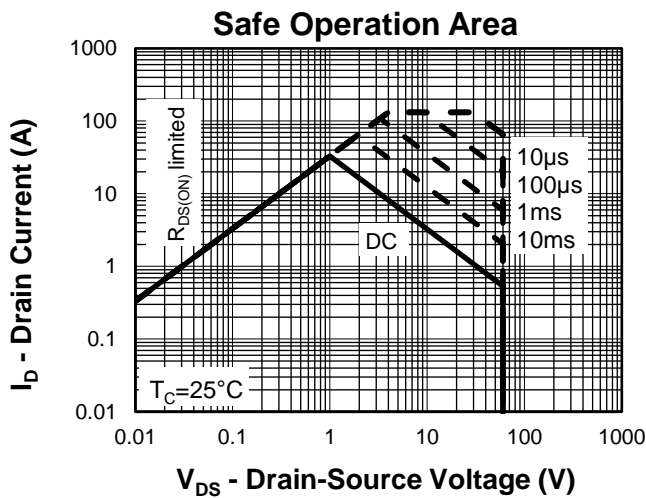
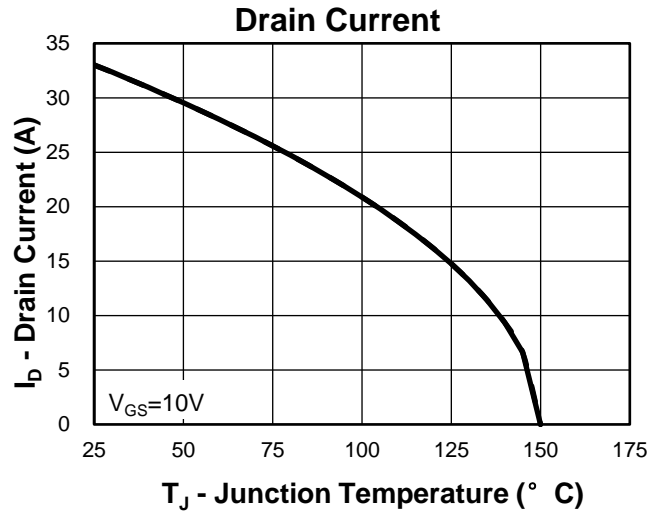
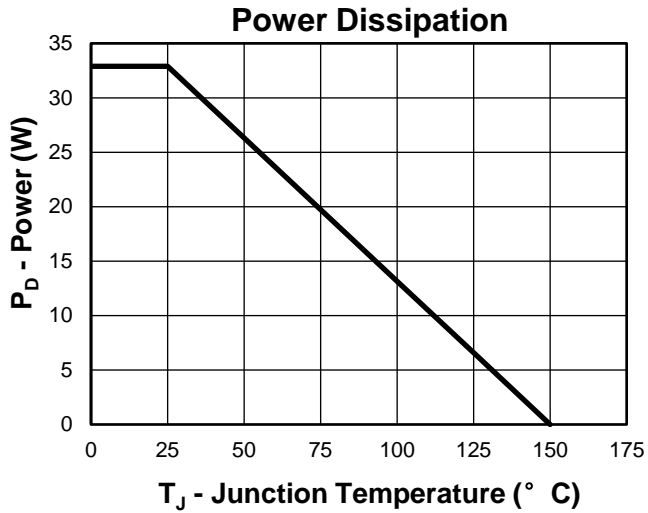
**Ordering and Marking Information**

Device	Package	Packaging	Quantity	Reel Size	Tape width
KS6210MB	PDFN3333	Tape&Reel	5000	13"	12mm

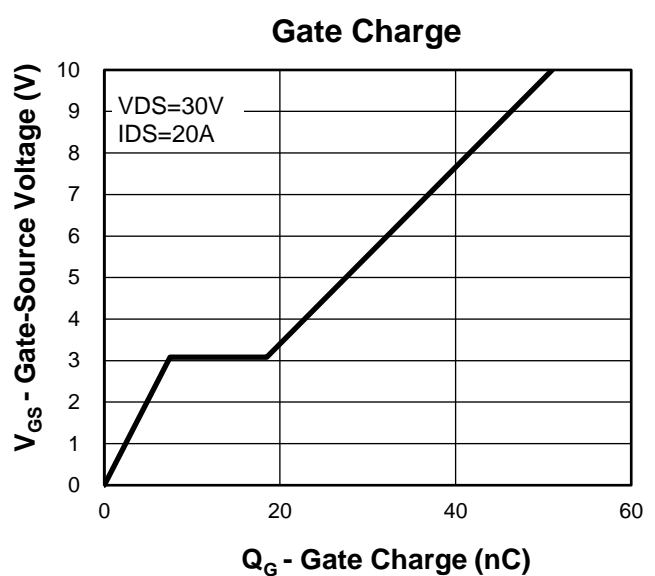
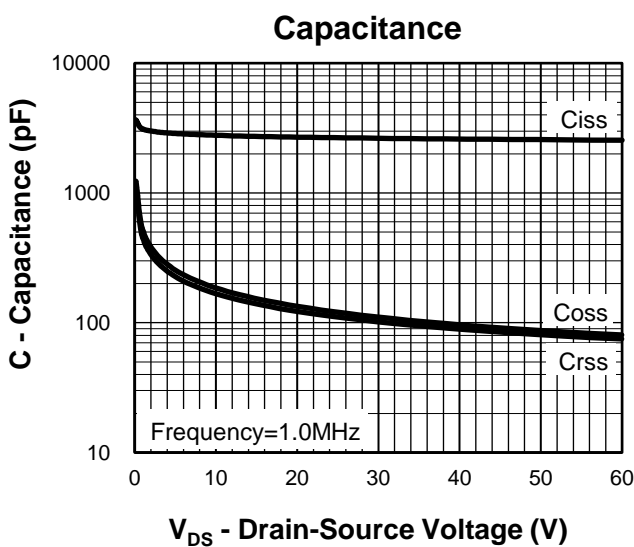
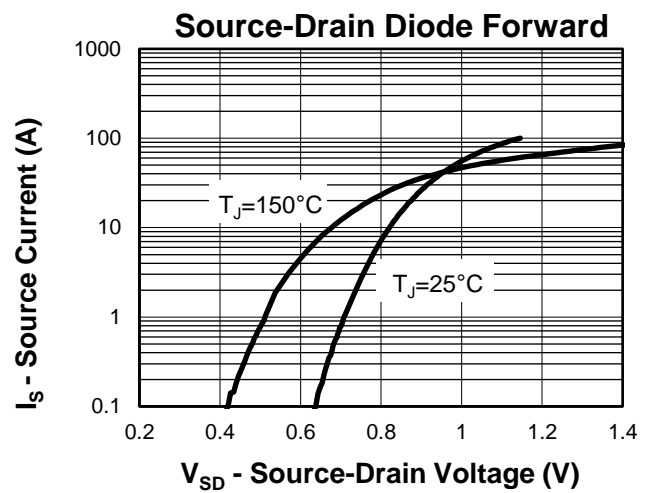
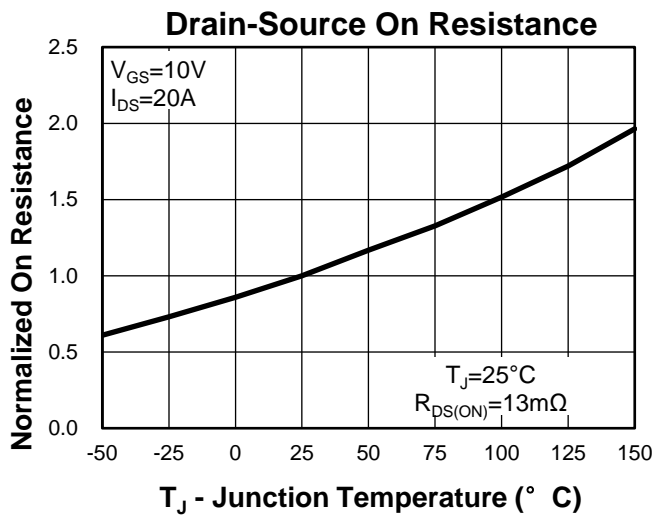
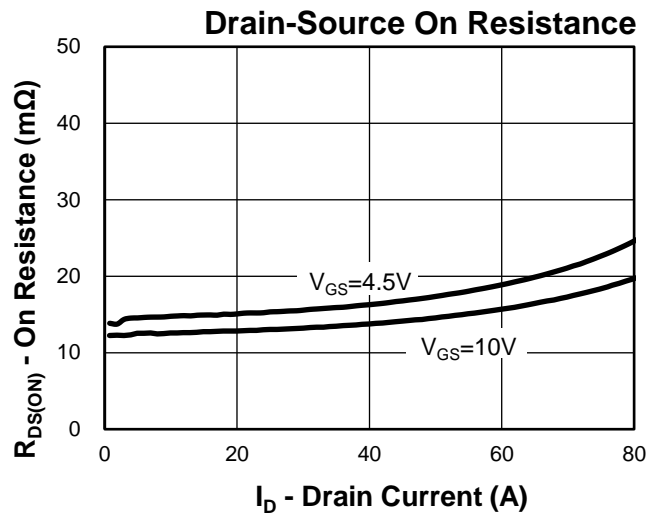
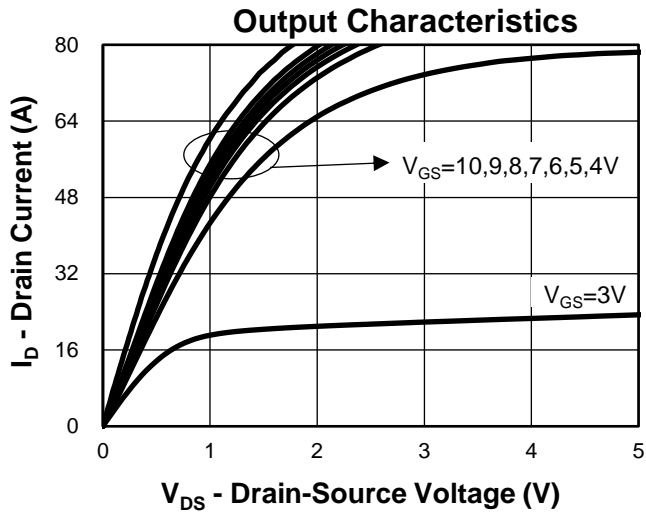


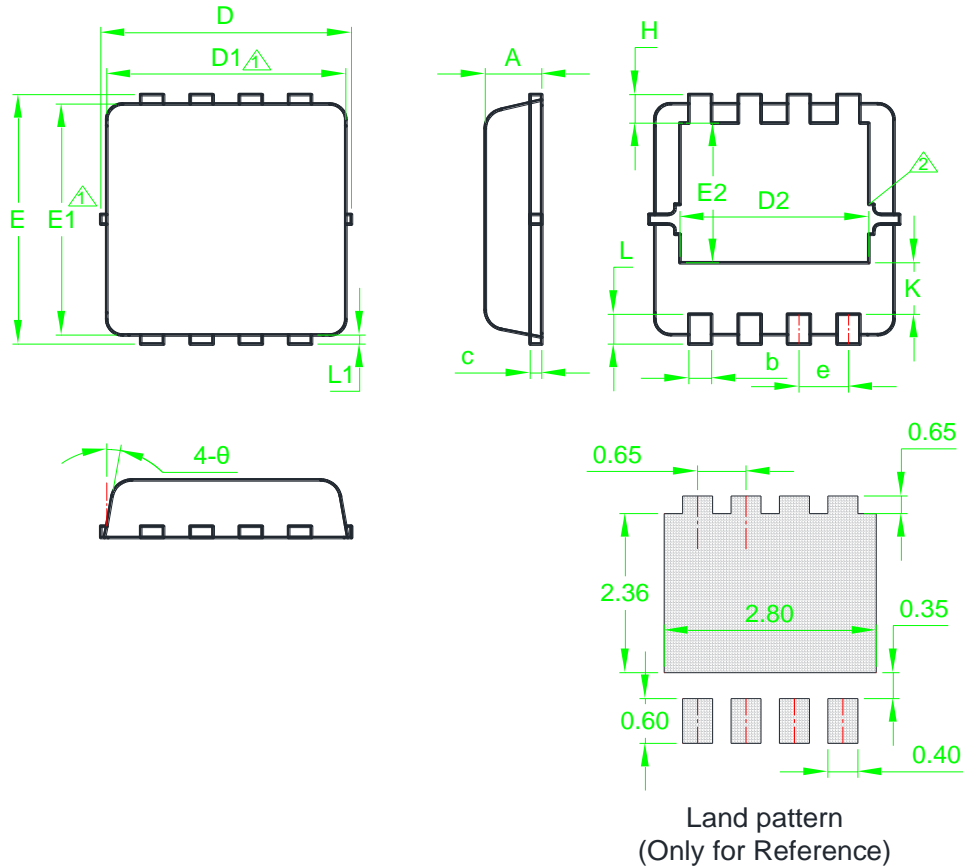
1st Line: Kwansemi Code(KS)  
 2nd Line: Part Number(6210)  
 3rd Line: Lot Number(YWWXXX)

### Typical Characteristics



### Typical Characteristics



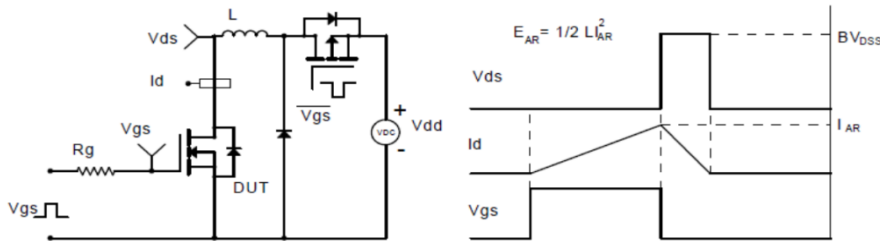
**Package Information**
**PDFN3333**


SYMBOL	MM			INCH			SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	0.70	0.80	0.90	0.028	0.031	0.035	E2	1.40	*	1.95	0.055	*	0.077
b	0.25	0.30	0.35	0.010	0.012	0.014	e	0.65BSC			0.026BSC		
c	0.10	0.20	0.30	0.004	0.008	0.012	H	0.30	0.40	0.50	0.012	0.016	0.020
D	3.20	3.30	3.40	0.126	0.130	0.134	K	0.50	*	*	0.020	*	*
D1	3.00	3.10	3.20	0.118	0.122	0.126	L	0.30	0.40	0.50	0.012	0.016	0.020
D2	2.35	2.45	2.55	0.093	0.096	0.100	L1	0.15BSC			0.006BSC		
E	3.20	3.30	3.40	0.126	0.130	0.134	θ	6°	*	12°	6°	*	12°
E1	2.90	3.05	3.20	0.114	0.120	0.126							

① Dimensions D1 and E1 do not include mold flash protrusions or gate burrs.

② The size and shape of exposed pad are variable depending on mold.

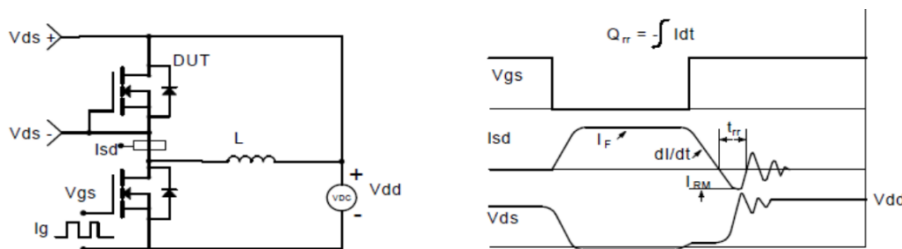
### Avalanche Test Circuit and Waveforms



### Switching Time Test Circuit and Waveforms



### Diode Recovery Test Circuit and Waveforms



### Gate Charge Test Circuit and Waveform



### Customer Service

Kwansemi Semiconductor Co.,Ltd

Email:Sales@kwansemi.com

Web:www.kwansemi.com

### DISCLAIMER:

Kwansemi reserves the right to change the specifications and circuitry without notice at any time. The Products are not designed for use in hostile environments, including, without limitation, aircraft, nuclear power generation, medical appliances, and devices or systems in which malfunction of any Product can reasonably be expected to result in a personal injury. Seller's customers using or selling Seller's products for use in such applications do so at their own risk and agree to fully defend and indemnify Seller.